

## Nanoanalysis of Metamorphic Magnetite using Field Ion Microscopy and Three- Dimensional Atom Probe

Kimberly R. Kuhlman,  
California Institute of Technology

Richard L. Martens & Thomas F. Kelly,  
Imago Scientific Instruments Corporation,  
University of Wisconsin - Madison

Neal D. Evans & Michael K. Miller  
Oak Ridge National Laboratory

Annual Meeting of the Geological Society of America  
November 13-16, 2000



  
California Institute of Technology



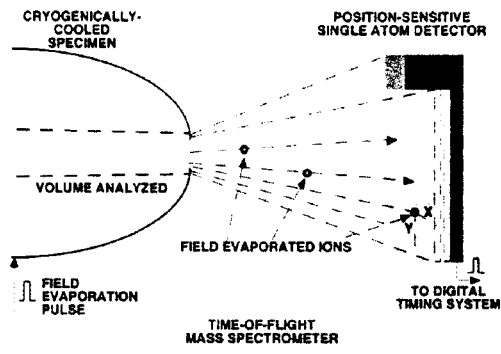
## Outline of Discussion

- Short tutorial on Field Ion Microscopy / 3D Atom Probe and why these techniques are interesting for geology and geomicrobiology.
- Discussion of sample preparation techniques for geological samples.
- Presentation of recent results of FIM and 3DAP of a metamorphic magnetite.



  
California Institute of Technology

## Schematic Illustration of APFIM Analysis

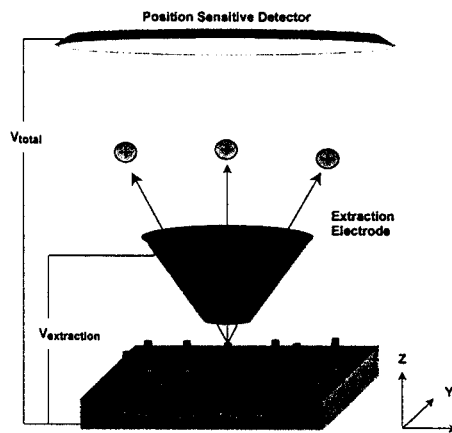


From Miller, et al. (1996) *Atom Probe Field Ion Microscopy*, Oxford University Press



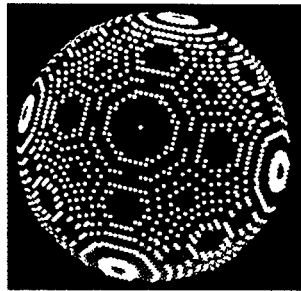
California Institute of Technology

## Schematic Illustration of LEAP Microscopy



California Institute of Technology

## Image Formation in the Field Ion Microscope (FIM)



The ball model illustrating the origin of FIM image contrast. The white atoms indicate sites above which field ionization occurs preferentially. The model is fcc with the (001) plane at the center and {111} planes on the edges.

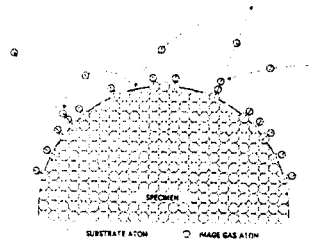


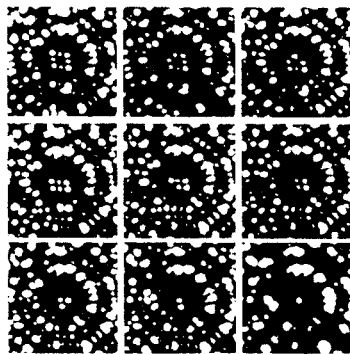
Image gas atoms (e.g. He, Ne, Ar, etc.) are polarized by the strong electric field, drawn to the surface, becoming field adsorbed. Electrons from the gas atoms tunnel into the metal and become field ionized. These image gas ions are then repelled from the sample towards the detector.



From Miller, et al. (1996) Atom Probe Field Ion Microscopy, Oxford University Press

**JPL**  
California Institute of Technology

## Evaporation of Single Atoms



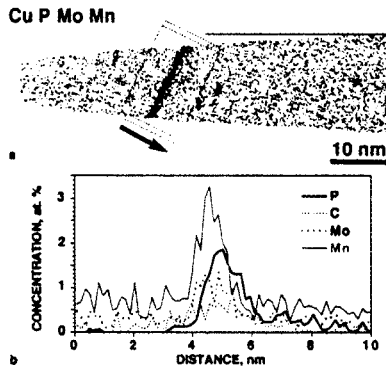
Sequence of FIM images showing evaporation of single atoms of a nickel zirconium into metallic specimen from the topmost atomic plane.



From Miller, et al. (1996) Atom Probe Field Ion Microscopy, Oxford University Press

**JPL**  
California Institute of Technology

## Analytical Capability of 3DAP



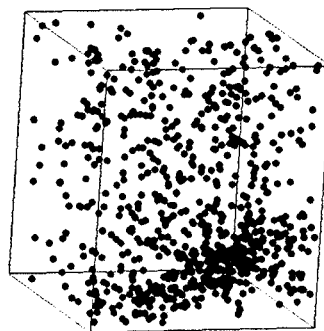
Atom probe analysis in the vicinity of an interface in a pressure vessel steel. Enrichments of P, C, Mo and Mn are evident.



From Miller (2000) *Atom Probe Tomography: Analysis at the Atomic Level*, Plenum Publishing Corporation.

JPL  
California Institute of Technology

## Analytical Capability of 3DAP

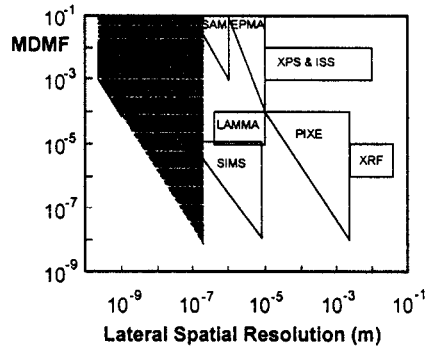


A three-dimensional image of stainless steel showing low levels of boron (red), carbon (green), and phosphorus (blue) at a grain boundary. This analysis was done using the conventional three-dimensional atom probe (3DAP) at Oak Ridge National Laboratory. Other elements (e.g. iron) have been left out of the image for clarity.



JPL  
California Institute of Technology

## Extending the Limits of Detection and Spatial Resolution



- Improvement in Minimum Detectable Mass Fraction (MDMF).
- Increase in Spatial Resolution compared to Secondary Ion Mass Spectrometry (SIMS).

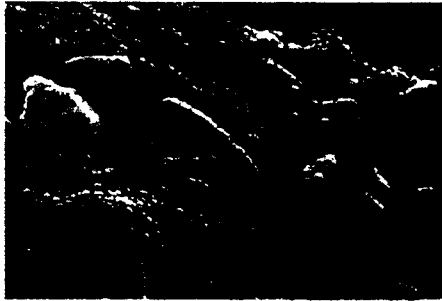


## Objectives of this work

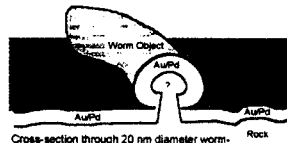
- A 3D near-atomic scale elemental map of a geological sample.
- Demonstrate the planetary science potential of the Local Electrode Atom Probe (LEAP).
  - Potential of LEAP analysis for non-conductive samples:
    - ✦ Terrestrial geology and geomicrobiology,
    - ✦ Apollo samples from the Moon,
    - ✦ Samples returned by the Stardust, Genesis and Mars missions.
- Demonstrate the potential of the Mini-LEAP for the *in-situ* analysis of planetary materials.
  - NASA is currently developing a prototype Mini-LEAP at JPL.



## "Nanobacteria" How do you characterize it?



An SEM micrograph of the "fossil nanobacteria" found in ALH84001 by McKay, et al. [1996].



Cross-section through 20 nm diameter worm-shaped object, coated with 7 nm of AuPd

A schematic diagram of a possible cause of the "fossil nanobacteria" found in ALH84001 by McKay, et al. (1996) as discussed by Steele, et al. (1998) and Bradley, et al. (1997).



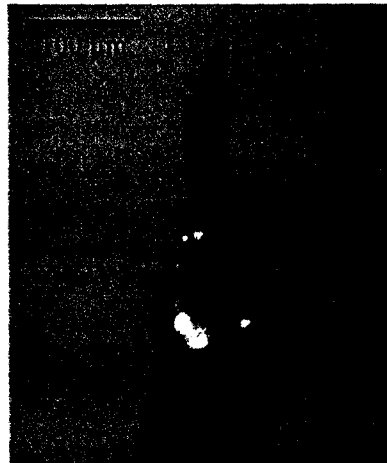
## Why Magnetite?

- > A common mineral on Earth, the Moon and Mars.
- > One of the more conductive minerals.
  - > Resistivity =  $52 \times 10^{-4}$  ohm-cm.
- > This particular magnetite contains disk-shaped exsolutions approx. 40 nm in diameter, 1-3 nm thick and about  $10^4$  platelets/ $\mu\text{m}^3$ .
- > EDS shows Mn and Al concentrated in these precipitates.
- > Quantitative analysis has been limited by the thickness of this second phase.

*Atom Probe is a technique that can potentially quantify the composition of these precipitates.*



## “Method of Sharp Shards”



- > Introduced by Camus, Melmed & Banfield in 1991.
- > Magnetite grains >2 mm in diameter were crushed at random to make sharp fragments 50 μm across and 250 μm long.
- > A single fragment is attached to a stainless steel insect pin using two-part, conductive silver epoxy.

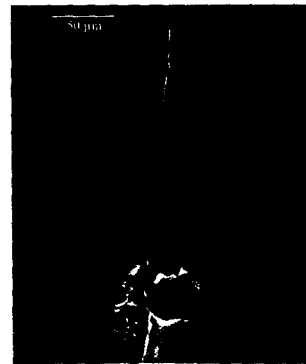


**JPL**  
California Institute of Technology

## Sample Shaping Using a FIB



Sample as mounted with Pt deposition at the base to improve electrical connection.

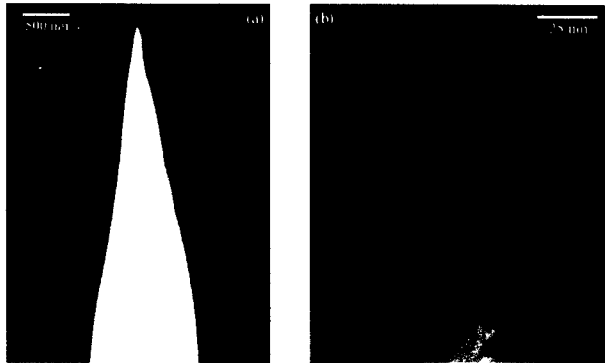


Sample after extensive ion milling using various beam currents and orientations.



**JPL**  
California Institute of Technology

## Magnetite Field Emission Tip Prepared with a FIB



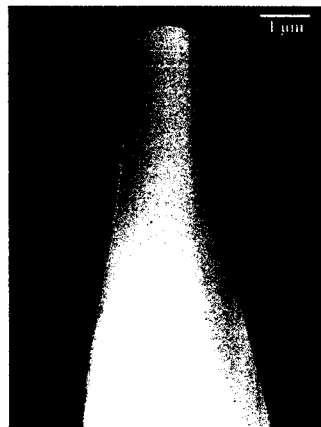
a) Profile of tip illustrating the smooth shank obtained. b) Sample tip showing radiation damage due to the 25 keV Ga beam.

Note that the damage decreases in thickness further down the shank of the sample.



JPL  
California Institute of Technology

## Post-Mortem Analysis of Magnetite Sample



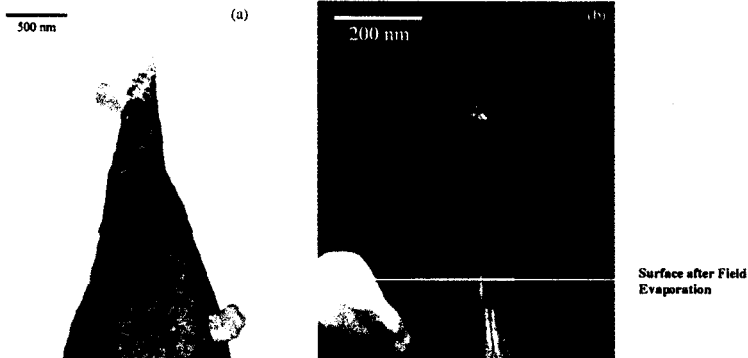
- TEM of sample 031300E after first analysis in the ECOPoSAP.
- Sample was analyzed to the voltage limit of 16 kV.
- Sample “flashed” near end of run.
- Note the slight roughness at the tip.



JPL  
California Institute of Technology



## Recovery of a Magnetite Field Emission Tip

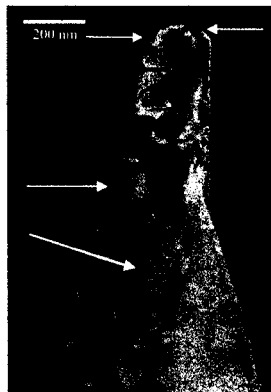


TEM of sample 031300E after resharping with a Gatan ion mill with 5 keV Ar and gun tilt = 40°. a) Bright field image showing precipitates and bend contour. b) High magnification image of the tip and precipitates seen in FIM images. The line indicates the surface obtained after field evaporation.



## Post Evaporation TEM Analysis of Magnetite LP204-1

Disk-shaped precipitates normal to the beam.

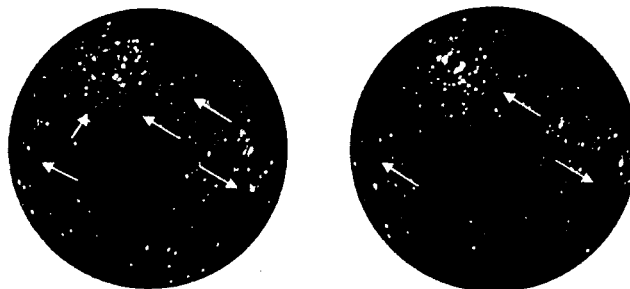


Precipitates seen in FIM images. The location of this surface is indicated on previous slide.

Electron diffraction pattern indicates that this view is normal to the [100].



## Field Ion Micrographs of Magnetite LP204-1



16 kV

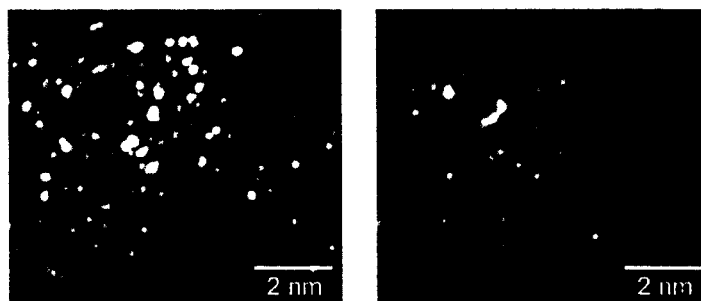
16.5 kV

Note the clarity of the {111} poles and the precipitates running directly through the pole at right of the images.



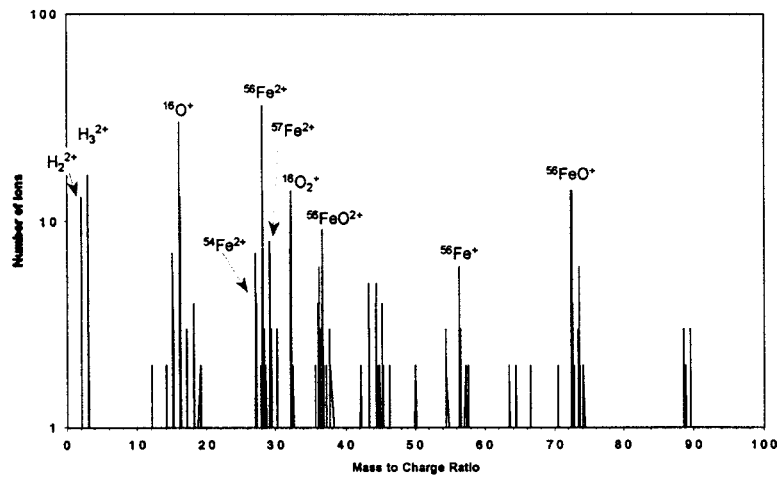
**JPL**  
California Institute of Technology

## Six-fold Symmetry of the {111} Planes



**JPL**  
California Institute of Technology

## First Mass Spectra from a Geological Material using Atom Probe



## Conclusion

- > First high quality FIM images of a bulk mineral.
- > Preliminary APFIM analysis of magnetite:
  - > Mass spectra have been obtained showing isotopes of Fe and O as well as FeO.
  - > Singly and doubly charged ions are observed.
  - > A preliminary mass spectrum taken from a precipitate contains both Mn and Al, as expected from previous analysis of magnetite LP204-1 by Sitzman, et al.
- > Traditionally non-conductive samples **CAN** be imaged and analyzed using APFIM.





## Acknowledgements

➤ **Research sponsored by:**

- Cross Enterprise Technology Development Program, U.S. National Aeronautics and Space Administration.
- Director's Research and Development Fund, Jet Propulsion Laboratory.
- Oak Ridge National Laboratory SHaRE User Facility and SHaRE Program.
  - ✦ *Division of Materials Sciences and Engineering, U.S. Department of Energy.*
  - ✦ *SHaRE Program with Oak Ridge Associated Universities.*

➤ **Special thanks to:**

- Professor John Valley of the University of Wisconsin for providing the samples of magnetite used in this work.
- William Carmichael and Glenn Boda of the Electron Microscopy Program at the Madison Area Technical College in Madison, WI for their assistance and for providing access to the focused ion beam.

